

Attorney Docket No. 04083/LH

**IN THE UNITED STATES PATENT  
AND TRADEMARK OFFICE**

Applicant(s): Takashi YONEYAMA, et al.

Serial No. : 10/773,524

Confirm. No.: 7190

Filed : February 6, 2004

For : DEFECT INSPECTION APPARATUS AND  
DEFECT INSPECTION METHOD

Art Unit : 2609

Examiner : Tsung Yin Tsai

**A M E N D M E N T**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

S I R :

This is responsive to the Office Action mailed May 11, 2007  
the extended term for response to which expires on October 11,  
2007.

**Amendments to the Specification** begin on page 2 of this  
paper.

**Amendments to the Claims** are set forth in the listing of  
claims which begins on page 4 of this paper. Claims 1, 5, 6, 8  
and 13-17 are canceled; claims 2, 3, 7 and 9-11 are amended;  
claims 18-26 are added; and claims 4 and 12 are maintained.

**Remarks** begin on page 13 of this paper.

This paper is being submitted  
via EFS-Web on October 11, 2007

In the event that this Paper is  
late filed, and the necessary  
petition for extension of time  
is not filed concurrently  
herewith, please consider this  
as a Petition for the requisite  
extension of time, and to the  
extent not already paid,  
authorization to charge the  
extension fee to Account  
No. 06-1378. In addition,  
authorization is hereby given to  
charge any fees for which  
payment has not been submitted,  
or to credit any overpayments,  
to Account No. 06-1378.